

SYSTEM AND METHOD FOR MEASURING CIRCUIT PERFORMANCE DEGRADATION DUE TO PFET NEGATIVE BIAS TEMPERATURE INSTABILITY (NBTI)

Abstract of the Disclosure

A ring oscillator (and test circuit incorporating the ring oscillator and test method therefor) includes an odd number of elements interconnected in a serially-connected infinite loop, each oscillator element having an associated programmable delay feature. The circuit can be used to measure effects of Negative Bias Temperature Instability (NBTI) in p-channel MOSFETs (PFETs).

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